

Assignment 3: Switched Capacitor Integrators and Filters

Objectives

- Understand the operation and non-idealities of the switched capacitor using a state-of-the art design kit and 65nm CMOS technology.
- To design a discrete-time bandpass filter using switched capacitor integrators and Cadence Analog Artist.

1. Preparation:

Study Chapter 14 in the textbook and the associated course slides.

You will use Cadence Analog Artist with the cmos65nm design kit and the svt MOSFETs from the *cmos065* library in all simulations, as in Assignment 1. You may use the same verilogA model for the opamp as in Assignment 1 or the single-input single-output *amp* cell from the Cadence ahdl library.

2. MOSFET switch simulation and modelling (5 points)

Consider the MOSFET switch test bench in Fig.1.

- a) Using the *port* cell from *analogLib* simulate the S-parameters of an SVT n-MOSFET with $L=60\text{nm}$, $W_f=1\mu\text{m}$ and $N_f=10$ from 100 MHz to 10 GHz and extract $C'_{gs}+C'_{sb}$ from $\text{imag}(Y_{11}+Y_{12})$ and $C'_{gd}+C'_{db}$ from $\text{imag}(Y_{22}+Y_{12})$ when the gate and substrate resistances are set to $0.1\ \Omega$ and $V_c = 0\text{ V}$, and calculate C_{OFF} per unit gate width as $C'_{\text{OFF}} = C'_{gs} + C'_{gd} + C'_{db} + C'_{sb}$. Extract the on-resistance per unit gate width, R'_{ON} , from $1/\text{real}(-Y_{12})$ when $V_c=1.1\text{V}$.

b) Repeat a) when the gate and substrate resistances are $10\text{ k}\Omega$. Explain the results and the implications. **(2 points)**

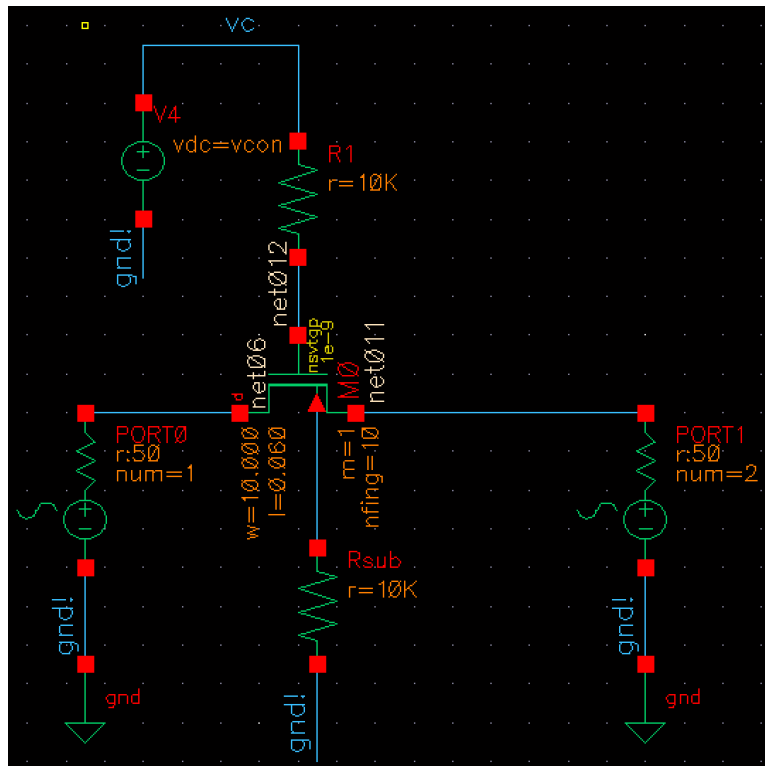


Fig.1 n-MOS switch testbench.

Consider the CMOS switched capacitor testbench in Fig.2 with identical-size SVT n-MOSFET and SVT p-MOSFET, each with $L=60\text{nm}$, $W_f=1\mu\text{m}$ and $N_f=5$ and a 200fF

capacitor. The sampling clock signals are 25% duty cycle and are non-overlapping. The clock signal can be as high as 2 GHz.

Simulate the signal waveforms at the input, output, and *store* nodes with an 500mV amplitude sinusoidal input signal at 50 MHz, clocked by a 2 GHz clock. **(1 point)**

What is the maximum error due to charge injection on the held output signal at the *store* node? **(1 point)**

What is the SDR (signal to distortion) at the output of the circuit? **(1 point)**

How does the maximum error due to charge injection change if the transistor size is increased by a factor of 10 i.e. 50 fingers, each 1 μ m wide? Explain why. **(1 point)**

How do the maximum error due to charge injection and SDR change if the switches are replaced by n-MOSFET switches? Explain. **(1 point)**

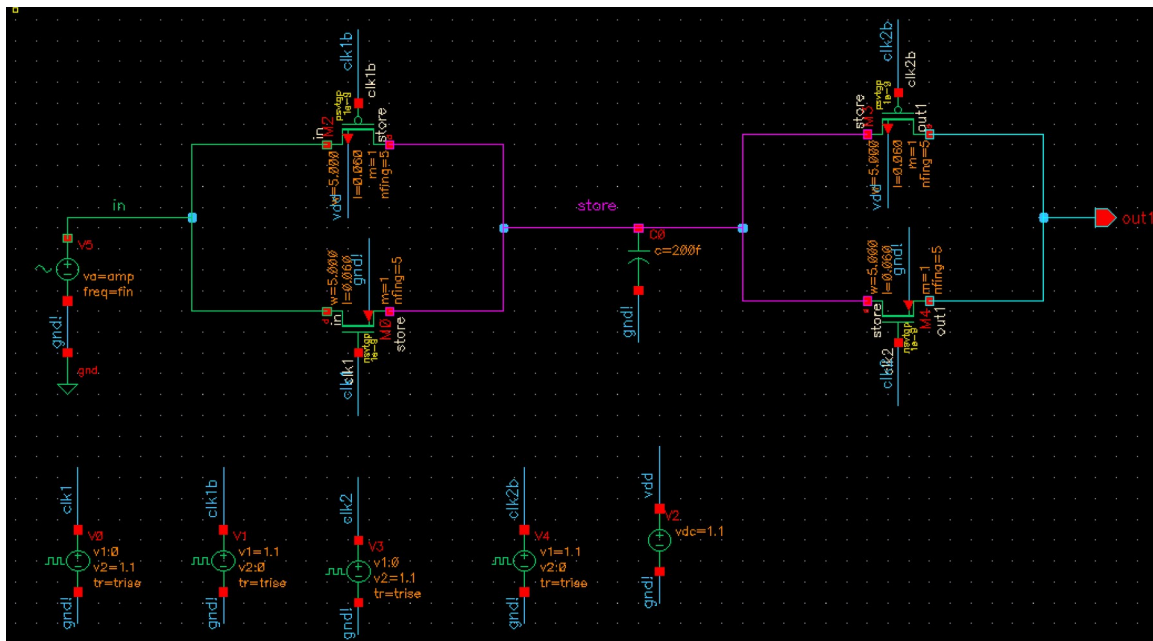


Fig. 2 CMOS switched capacitor test bench.

4. Discrete-Time Bandpass Filter Design (10 points)

Design a bandpass filter with the specification in Table 1 using the Biquad schematic in Fig. 14.28 in the textbook.

- Provide the z -transfer function, schematic with all the component values, and the hand design equations. **(5 points)**
- Plot the simulated signal waveforms at the input and at the output for an input signal amplitude of 500mV amplitude at the centre frequency. **(2 points)**
- Plot the output spectrum for a two-tone test at $V_{in} = 10\text{mV}$ and $V_{in} = 100\text{mV}$ amplitude and calculate the IIP3. **(3 points)**

Table 1

| Surname starts with | f_{osc} (GHz) | Q | Gain |
|---------------------|-----------------|----|------|
| A, B, C, D | 200 MHz | 4 | 1 |
| E, F, G, H, | 220 MHz | 6 | 1 |
| I, J, K, L | 180 MHz | 8 | 0.8 |
| M, N, O, P | 160 MHz | 10 | 0.9 |
| Q, R, S, T | 160 MHz | 6 | 0.9 |
| U, V, X, Y, Z | 200 MHz | 8 | 0.8 |

Supply voltage and control voltage is 1.1V or lower.